## Notice of References Cited Application/Control No. 10/676,728 Examiner A. Dexter Tugbang Applicant(s)/Patent Under Reexamination BEDELL ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,141,623	08-1992	Cohen et al.	204/192.34 x
*	В	US-5,853,960	12-1998	Tran et al.	216/2 x
*	С	US-6,278,591	08-2001	Chang et al.	360/126 x
*	D	US-6,469,875	10-2002	Chen et al.	29/603.16 x
*.	Ε	US-2004/0052009	03-2004	Ohtsu et al.	360/324.12
*	F	US-6,779,249	08-2004	Santini, Hugo Alberto Emilio	29/603.15 x
	G	US ,			
	Η	US-			
	ı	US-			
	J	US-			
7	К	US-		·	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Gorman et al., "Recording Studies of Sub-Micron Write Heads by Focused Ion Beam Trimming", IEEE Transactions on Magnetics, Vol. 33, No. 5, Sept 1997, pages 2824-2826.
	<b>v</b>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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